



PRELIMINARY

SOLID STATE DEVICES, INC

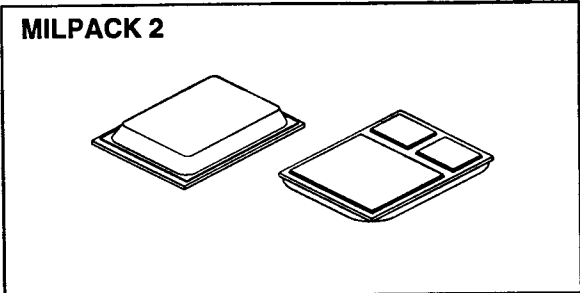
14849 Firestone Boulevard · La Mirada, CA 90638  
Phone: (714) 670-SSDI (7734) · Fax: (714) 522-7424

**SFF10N100B**

**10 AMP  
1000 VOLTS  
1.2 Ω  
N-CHANNEL  
POWER MOSFET**

**Designer's Data Sheet**

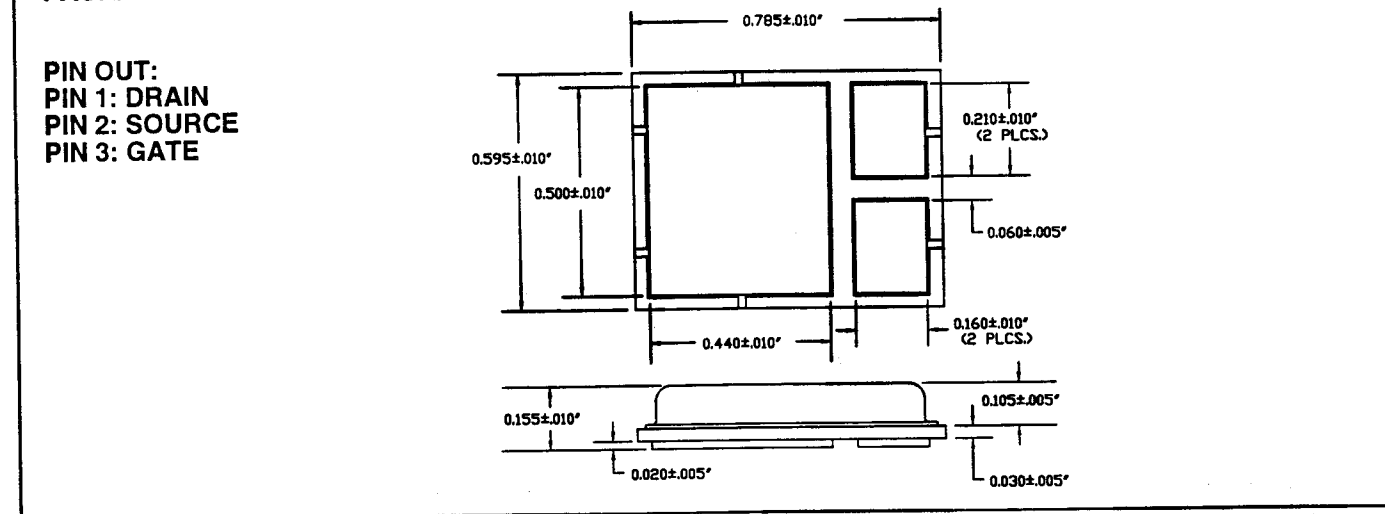
- FEATURES:**
- Rugged construction with polysilicon gate
  - Low RDS(on) and high transconductance
  - Excellent high temperature stability
  - Very fast switching speed
  - Fast recovery and superior dv/dt performance
  - Increased reverse energy capability
  - Low input and transfer capacitance for easy paralleling
  - Hermetically sealed surface mount power package
  - TX, TXV and Space Level screening available
  - Replaces: IXTH10N100 Types



**MAXIMUM RATINGS:**

CHARACTERISTIC	SYMBOL	VALUE	UNIT
Drain to Source Voltage	V <sub>DS</sub>	1000	Volts
Gate to Source Voltage	V <sub>GS</sub>	±20	Volts
Continuous Drain Current	I <sub>D</sub>	10	Amps
Operating and Storage Temperature	T <sub>op</sub> & T <sub>stg</sub>	-55 to +150	°C
Thermal Resistance, Junction to Case	R <sub>θJC</sub>	0.5	°C/W
Total Device Dissipation @ TC=25°C	P <sub>D</sub>	250	Watts
Total Device Dissipation @ TC=55°C		190	

**PACKAGE OUTLINE: MILPACK 2**



**NOTE:** All specifications are subject to change without notification. SCD's for these devices should be reviewed by SSDI prior to release.

**DATA SHEET #: F00185 C**

**MED**

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## ELECTRICAL CHARACTERISTICS @ $T_J=25^\circ\text{C}$ (Unless Otherwise Specified)

RATING	SYMBOL	MIN	TYP	MAX	UNIT
Drain to Source Breakdown Voltage ( $V_{GS}=0\text{ V}$ , $I_D=3\text{ mA}$ )	$BV_{DSS}$	1000	---	---	V
Drain to Source on State Resistance ( $V_{GS}=10\text{ V}$ , $I_D=50\%$ Rated ID)	$R_{DS(on)}$	---	1.05	1.2	$\Omega$
On State Drain Current ( $V_{DS}=15\text{ V}$ , $V_{GS}=10\text{ V}$ )	$I_{D(on)}$	10	---	---	A
Gate Threshold Voltage ( $V_{DS}\geq V_{GS}$ , $I_D=4\text{ mA}$ )	$V_{GS(th)}$	2.0	---	4.5	V
Forward Transconductance ( $V_{DS}>I_{D(on)} \times R_{DS(on)}$ Max, $I_{DS}=50\%$ rated ID)	$g_{fs}$	5	8	---	$S(\bar{V})$
Zero Gate Voltage Drain Current ( $V_{DS}=\text{max rated voltage}$ , $V_{GS}=0\text{ V}$ ) ( $V_{DS}=80\%$ rated VDS, $V_{GS}=0\text{ V}$ , $T_A=125^\circ\text{C}$ )	$I_{DSS}$	---	---	250 1000	$\mu\text{A}$
Gate to Source Leakage Forward Gate to Source Leakage Reverse	At rated VGS $I_{GSS}$	---	---	+100 -100	nA
Total Gate Charge Gate to Source Charge Gate to Drain Charge	$V_{GS}=10\text{ Volts}$ 50% rated VDS Rated ID $Q_g$ $Q_{gs}$ $Q_{gd}$	---	110 20 40	155 45 80	nC
Turn on Delay Time Rise Time Turn Off Delay Time Fall Time	$V_{DD}=50\%$ rated VDS 50% rated ID $R_G=6.2\Omega$ $V_{GS}=10\text{ V}$ $t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	---	30 20 110 40	50 50 130 50	nsec
Diode Forward Voltage ( $I_S=\text{rated ID}$ , $V_{GS}=0\text{ V}$ , $T_J=25^\circ\text{C}$ )	$V_{SD}$	---	---	1.5	V
Diode Reverse Recovery Time Reverse Recovery Charge	$T_J=25^\circ\text{C}$ $I_F=\text{rated ID}$ $di/dt=100\text{ A}/\mu\text{sec}$ $t_{rr}$ $Q_{RR}$	---	850 ---	1200 ---	nsec $\mu\text{C}$
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{GS}=0\text{ Volts}$ $V_{DS}=25\text{ Volts}$ $f=1\text{ MHz}$ $C_{iss}$ $C_{oss}$ $C_{rss}$	---	4000 310 70	---	pF

SAFE OPERATING AREA (S.O.A.)  
 $T_C = 25^\circ\text{C}$ , D.C. CONDITION

